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*Rong-Jian Chen; Bin-Chang Chieu;*

Pattern Recognition, 1992. Vol.III. Conference C: Image, Speech and Signal Analysis, Proceedings., 11th IAPR International Conference on , 30 Aug.-3 Se 1992

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**1 Joint optimization of block size and quantization for quadtree-based motion estimation**
*Jungwoo Lee;*

 Image Processing, IEEE Transactions on , Volume: 7 , Issue: 6 , June 1998  
 Pages:909 - 912

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**2 An adaptive hierarchical image coding technique using transform v quantization**
*Jihong Zhang; Youli Bao;*

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